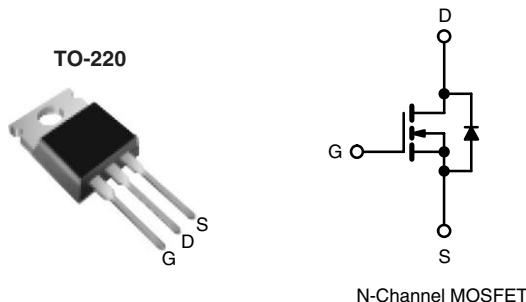


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	400	
$R_{DS(on)}$ (Ω)	$V_{GS} = 10$ V	5.5
Q_g (Max.) (nC)	22	
Q_{gs} (nC)	5.8	
Q_{gd} (nC)	9.3	
Configuration	Single	



FEATURES

- Low Gate Charge Q_g results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective Coss Specified (See AN1001)
- Lead (Pb)-free Available



APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Single Transistor Flyback Xfmr. Reset
- Single Transistor Forward Xfmr. Reset
(Both US Line Input Only)

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRF730APbF SiHF730A-E3
SnPb	IRF730A SiHF730A

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Gate-Source Voltage		V_{GS}	± 30	V
Continuous Drain Current	V_{GS} at 10 V	I_D	5.5	A
			3.5	
Pulsed Drain Current ^a			22	
Linear Derating Factor			0.6	W/°C
Single Pulse Avalanche Energy ^b		E_{AS}	290	mJ
Repetitive Avalanche Current ^a		I_{AR}	5.5	A
Repetitive Avalanche Energy ^a		E_{AR}	7.4	mJ
Maximum Power Dissipation	$T_C = 25$ °C	P_D	74	W
Peak Diode Recovery dV/dt ^c		dV/dt	4.6	V/ns
Operating Junction and Storage Temperature Range		T_J, T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	
Mounting Torque	6-32 or M3 screw		10	lbf · in
			1.1	N · m

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting $T_J = 25$ °C, $L = 19$ mH, $R_G = 25 \Omega$, $I_{AS} = 5.5$ A (see fig. 12).
- $I_{SD} \leq 5.5$ A, $dI/dt \leq 90$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
- 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

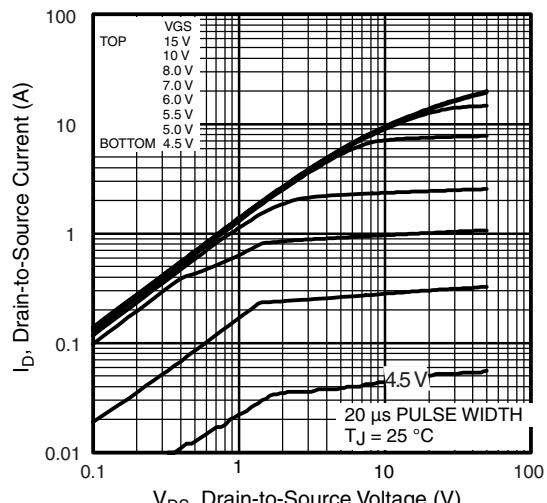
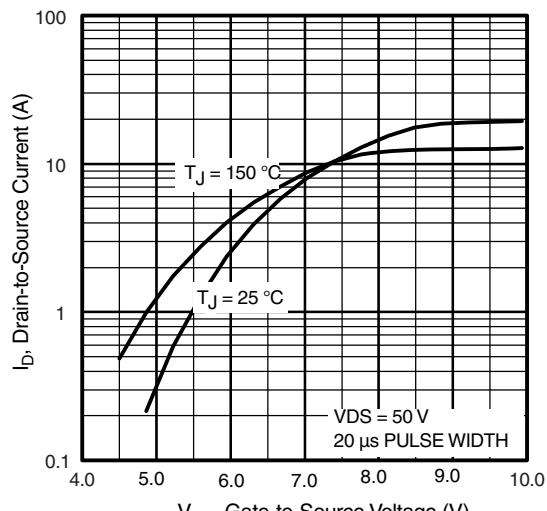
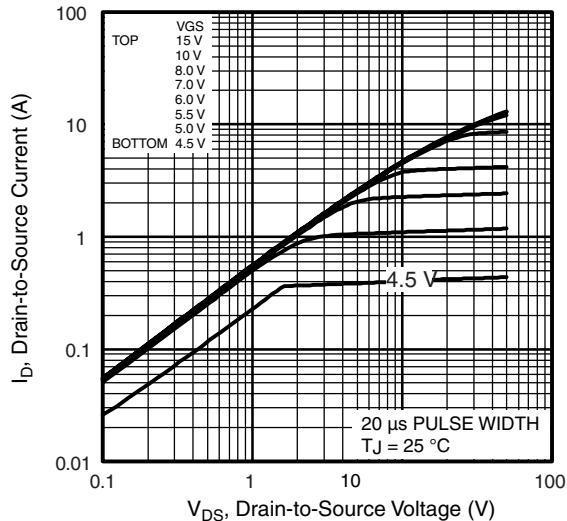
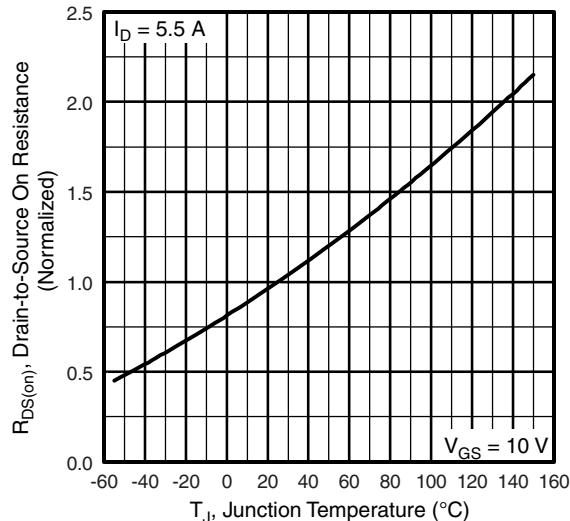
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.70	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Ambient	R_{thJA}	-	62	

SPECIFICATIONS $T_J = 25^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	400	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$	-	0.5	-	$\text{V}/^{\circ}\text{C}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	2.0	-	4.5	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 400 \text{ V}$, $V_{GS} = 0 \text{ V}$	-	-	25	μA
		$V_{DS} = 320 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^{\circ}\text{C}$	-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 3.3 \text{ A}^b$	-	-	1.0
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$	$I_D = 3.3 \text{ A}$	3.1	-	-
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5	-	600	-	pF
Output Capacitance	C_{oss}		-	103	-	
Reverse Transfer Capacitance	C_{rss}		-	4.0	-	
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$	-	890	
			$V_{DS} = 320 \text{ V}$, $f = 1.0 \text{ MHz}$	-	30	
			$V_{DS} = 0 \text{ V}$ to 320 V^c	-	45	
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 3.5 \text{ A}$, $V_{DS} = 320 \text{ V}$ see fig. 6 and 13 ^b	-	-	22
Gate-Source Charge	Q_{gs}			-	-	5.8
Gate-Drain Charge	Q_{gd}			-	-	9.3
Turn-On Delay Time	$t_{d(on)}$			-	10	-
Rise Time	t_r	$V_{DD} = 200 \text{ V}$, $I_D = 3.5 \text{ A}$ $R_G = 12 \Omega$, $R_D = 57 \Omega$, see fig. 10 ^b	-	22	-	ns
Turn-Off Delay Time	$t_{d(off)}$		-	20	-	
Fall Time	t_f		-	16	-	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode	-	-	5.5	A
Pulsed Diode Forward Current ^a	I_{SM}		-	-	22	
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}\text{C}$, $I_S = 5.5 \text{ A}$, $V_{GS} = 0 \text{ V}^b$	-	-	1.6	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^{\circ}\text{C}$, $I_F = 3.5 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$	-	370	550	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	1.6	2.4	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.
c. $C_{oss\ eff}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS} .

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics

Fig. 4 - Normalized On-Resistance vs. Temperature

IRF730A, SiHF730A



Vishay Siliconix

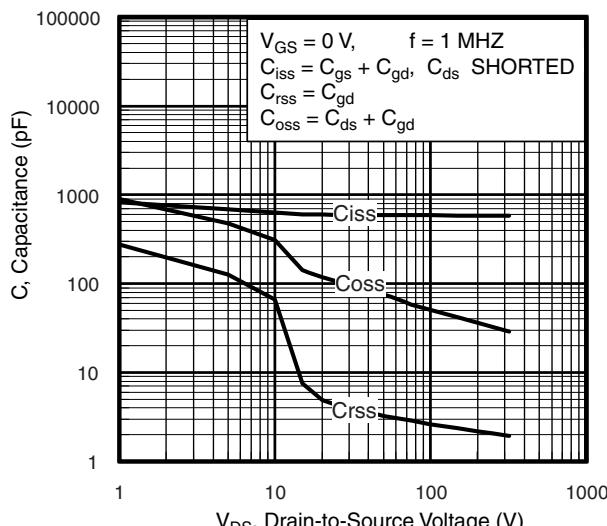


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

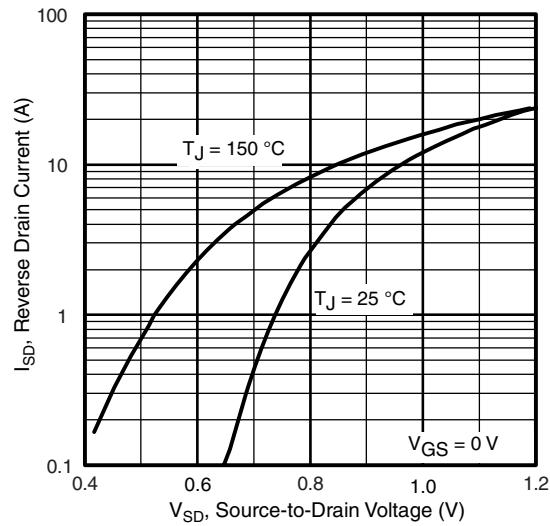


Fig. 7 - Typical Source-Drain Diode Forward Voltage

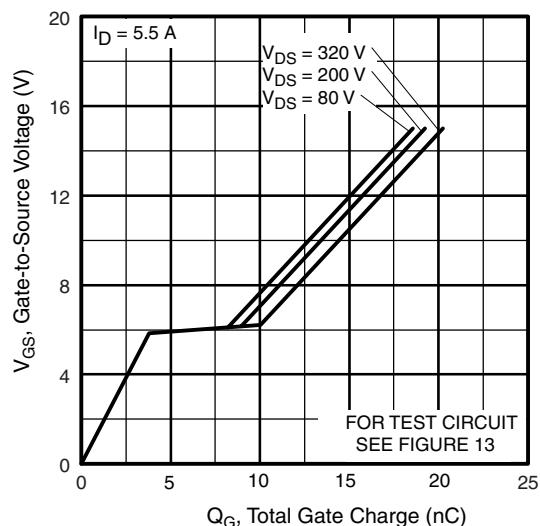


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

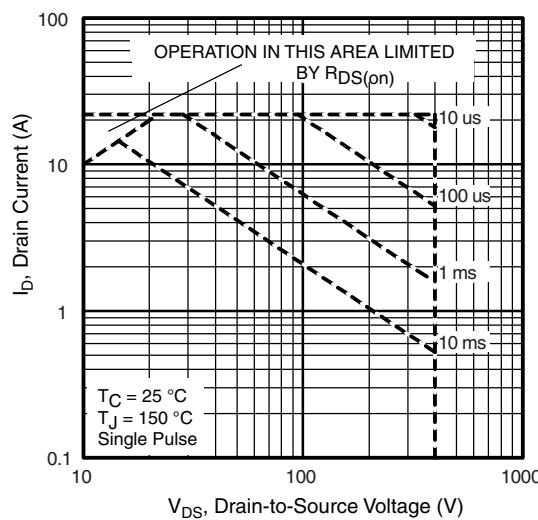


Fig. 8 - Maximum Safe Operating Area

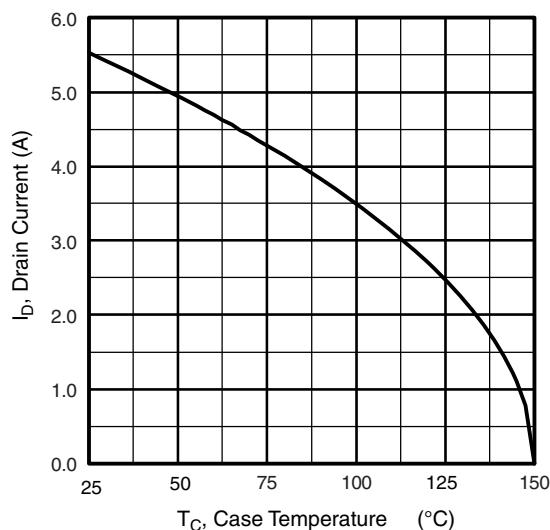


Fig. 9 - Maximum Drain Current vs. Case Temperature

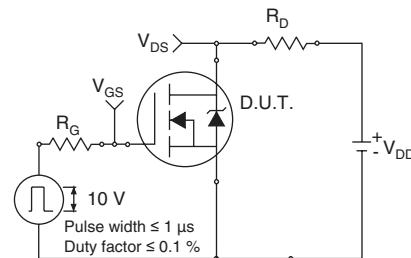


Fig. 10a - Switching Time Test Circuit

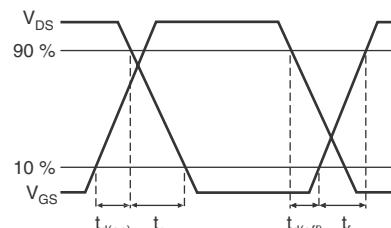


Fig. 10b - Switching Time Waveforms

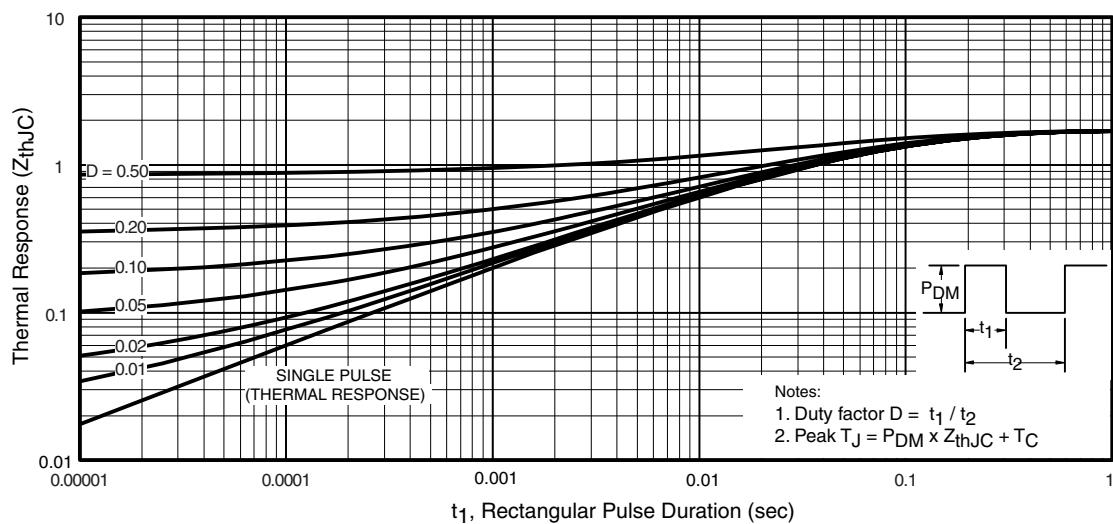


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

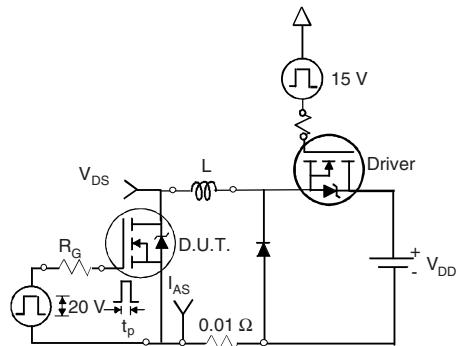


Fig. 12a - Unclamped Inductive Test Circuit

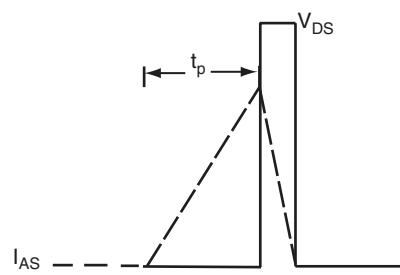


Fig. 12b - Unclamped Inductive Waveforms

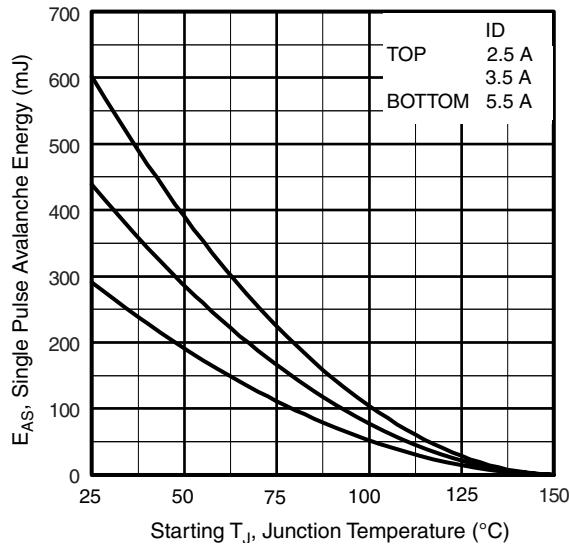


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

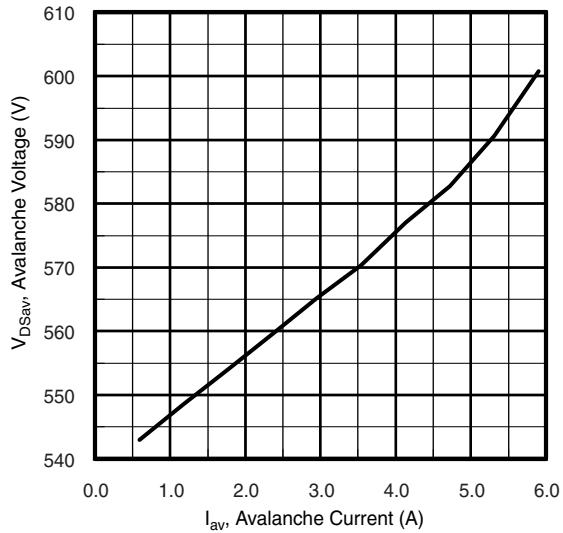


Fig. 12d - Typical Drain Source Voltage vs. Avalanche Current

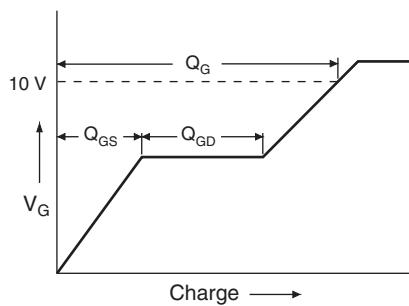


Fig. 13a - Basic Gate Charge Waveform

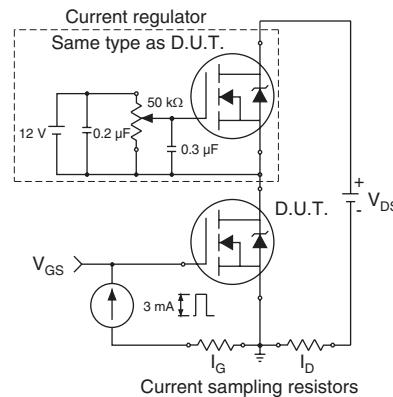
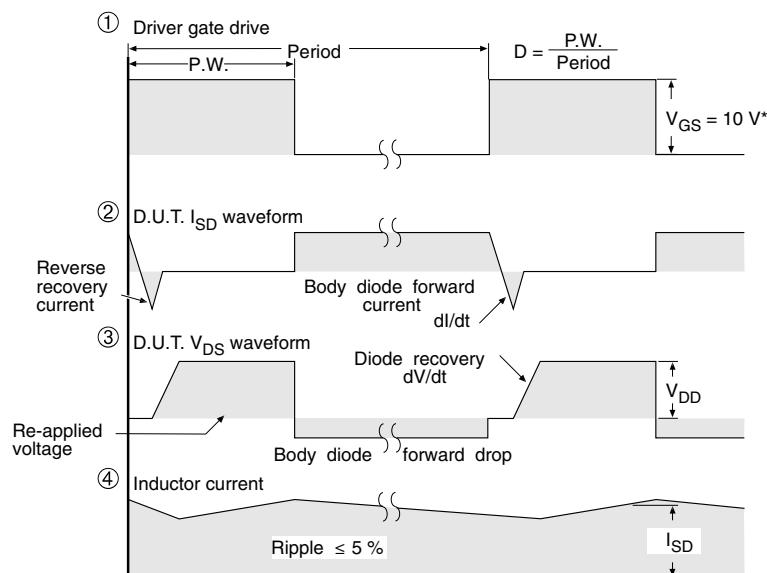
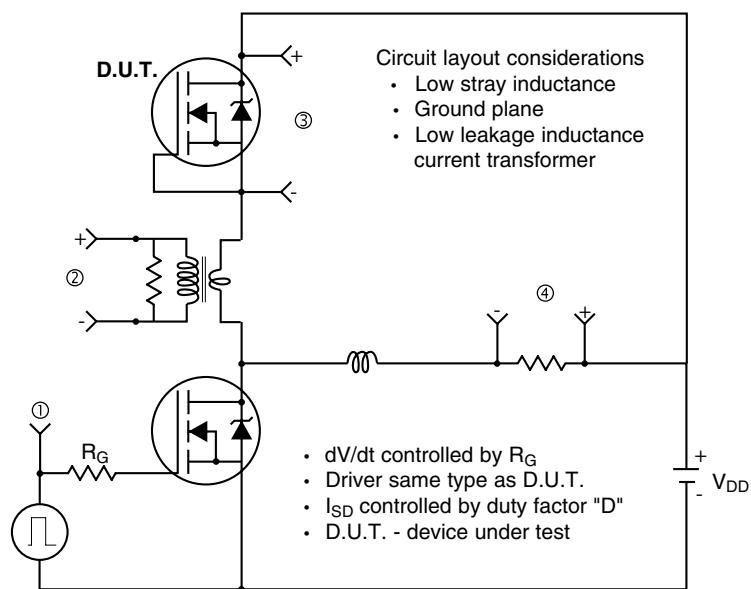


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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